

HEXFRED® Ultrafast Soft Recovery Diode, 200 A


SOT-227
FEATURES

- Fast recovery time characteristic
- Electrically isolated base plate
- Large creepage distance between terminal
- Simplified mechanical designs, rapid assembly
- UL approved file E78996
- Compliant to RoHS directive 2002/95/EC
- Designed and qualified for industrial level


**RoHS
COMPLIANT**
PRODUCT SUMMARY

V_R	1200 V
V_F (typical)	2.7 V
t_{rr} (typical)	150 ns
$I_{F(DC)}$ at T_C	100 A at 69 °C

DESCRIPTION/APPLICATIONS

The dual diode series configuration (HFA200FA120P) is used for output rectification or freewheeling/clamping operation and high voltage application.

The semiconductor in the SOT-227 package is isolated from the copper base plate, allowing for common heatsinks and compact assemblies to be built.

These modules are intended for general applications such as HV power supplies, electronic welders, motor control and inverters.

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	TEST CONDITIONS	MAX.	UNITS
Cathode to anode voltage	V_R		1200	V
Continuous forward current	I_F	$T_C = 69\text{ °C}$	100	A
Single pulse forward current	I_{FSM}	$T_J = 25\text{ °C}$	900	
Maximum repetitive forward current	I_{FRM}	Rated V_R , square wave, 20 kHz, $T_C = 60\text{ °C}$	150	
Maximum power dissipation	P_D	$T_C = 25\text{ °C}$	416	W
		$T_C = 100\text{ °C}$	166	
RMS isolation voltage	V_{ISOL}	Any terminal to case, $t = 1\text{ minute}$	2500	V
Operating junction and storage temperature range	T_J, T_{Stg}		- 55 to + 150	°C

ELECTRICAL SPECIFICATIONS ($T_J = 25\text{ °C}$ unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Cathode to anode breakdown voltage	V_{BR}	$I_R = 100\text{ }\mu\text{A}$	1200	-	-	V
Forward voltage	V_{FM}	$I_F = 100\text{ A}$	-	2.68	3.6	
		$I_F = 200\text{ A}$	-	3.37	4.7	
		$I_F = 100\text{ A}, T_J = 150\text{ °C}$	-	2.7	2.9	
Reverse leakage current	I_{RM}	$V_R = V_R\text{ rated}$	-	10	75	μA
		$T_J = 125\text{ °C}, V_R = V_R\text{ rated}$	-	2	-	mA

DYNAMIC RECOVERY CHARACTERISTICS ($T_J = 25\text{ °C}$ unless otherwise specified)						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Reverse recovery time	t_{rr}	$T_J = 25\text{ °C}$	-	150	-	ns
		$T_J = 125\text{ °C}$	-	237	-	
Peak recovery current	I_{RRM}	$T_J = 25\text{ °C}$	-	14	-	A
		$T_J = 125\text{ °C}$	-	21	-	
Reverse recovery charge	Q_{rr}	$T_J = 25\text{ °C}$	-	1050	-	nC
		$T_J = 125\text{ °C}$	-	2430	-	

THERMAL - MECHANICAL SPECIFICATIONS						
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNITS
Junction to case, single leg conducting	R_{thJC}		-	-	0.3	°C/W
Junction to case, both legs conducting			-	-	0.15	
Case to heatsink	R_{thCS}	Flat, greased and surface	-	0.05	-	
Weight			-	30	-	g
Mounting torque			-	1.3	-	Nm

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Vishay Semiconductors

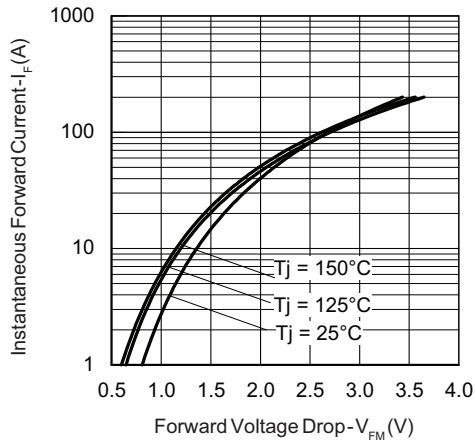


Fig. 1 - Typical Forward Voltage Drop Characteristics

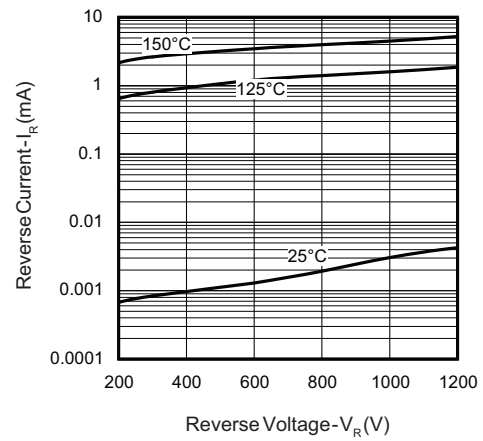


Fig. 2 - Typical Values of Reverse Current vs. Reverse Voltage

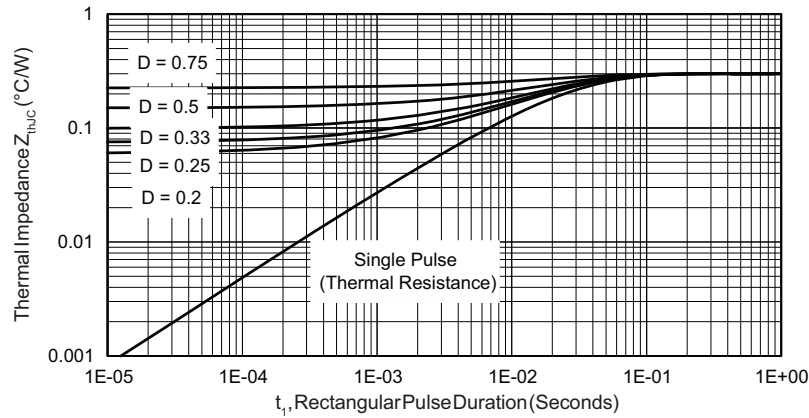
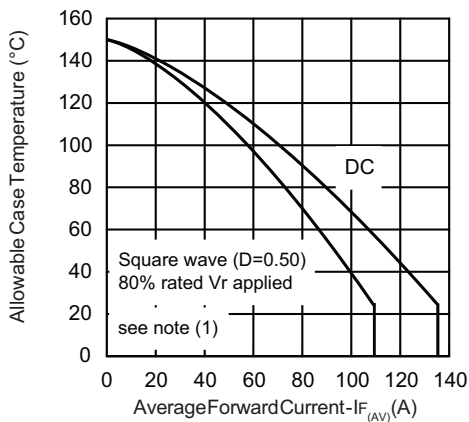

 Fig. 3 - Maximum Thermal Impedance Z_{thJC} Characteristics


Fig. 4 - Maximum Allowable Case Temperature vs. Average Forward Current

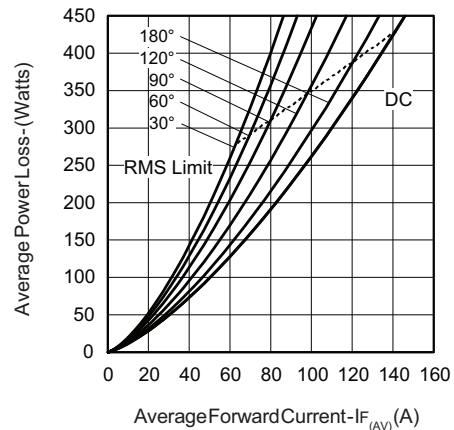


Fig. 5 - Forward Power Loss Characteristics

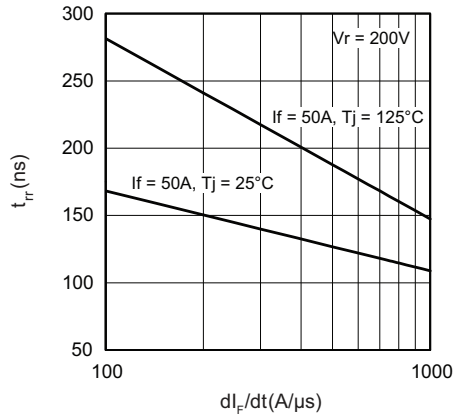


Fig. 6 - Typical Reverse Recovery Time vs. dI_F/dt

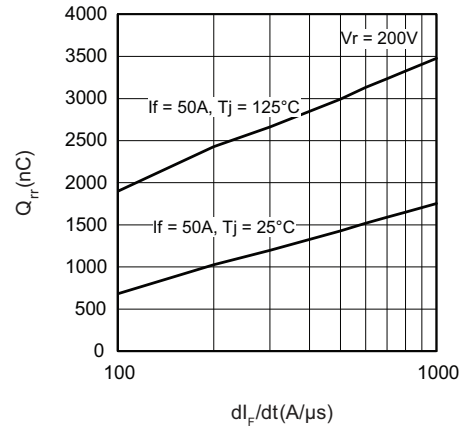


Fig. 7 - Typical Stored Charge vs. dI_F/dt

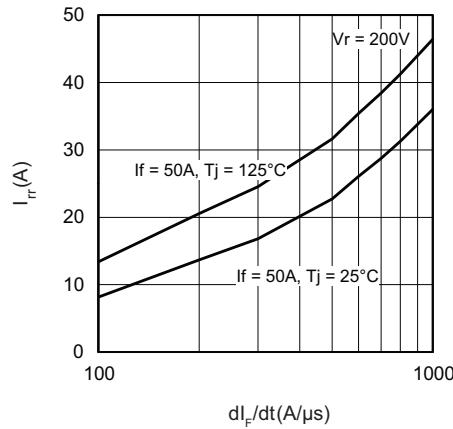


Fig. 8 - Typical Peak Recovery Current vs. dI_F/dt

Note

- (1) Formula used: $T_C = T_J - (P_d + P_{d_{REV}}) \times R_{thJC}$;
- P_d = Forward power loss = $I_{F(AV)} \times V_{FM}$ at $(I_{F(AV)}/D)$ (see fig. 5);
- $P_{d_{REV}}$ = Inverse power loss = $V_{R1} \times I_R (1 - D)$; I_R at V_{R1} = Rated V_R

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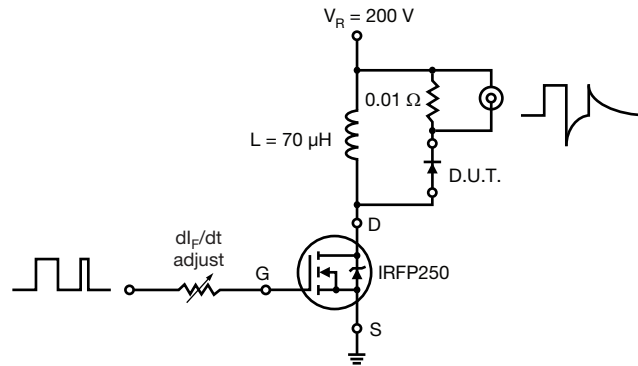
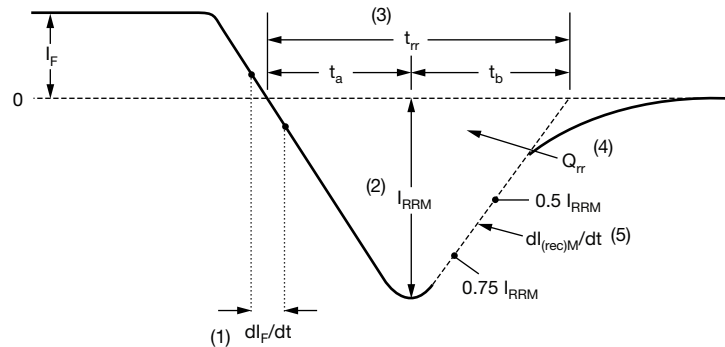


Fig. 9 - Reverse Recovery Parameter Test Circuit


 (1) dI_F/dt - rate of change of current through zero crossing

 (2) I_{RRM} - peak reverse recovery current

 (3) t_{rr} - reverse recovery time measured from zero crossing point of negative going I_F to point where a line passing through $0.75 I_{RRM}$ and $0.50 I_{RRM}$ extrapolated to zero current.

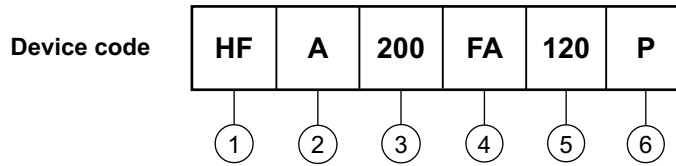
 (4) Q_{rr} - area under curve defined by t_{rr} and I_{RRM}

$$Q_{rr} = \frac{t_{rr} \times I_{RRM}}{2}$$

 (5) $dI_{(rec)M}/dt$ - peak rate of change of current during t_b portion of t_{rr}

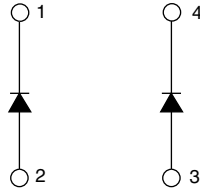
Fig. 10 - Reverse Recovery Waveform and Definitions

ORDERING INFORMATION TABLE



- 1** - HEXFRED® family
- 2** - Process designator (A = Electron irradiated)
- 3** - Average current (200 = 200 A)
- 4** - Package outline (FA = SOT-227)
- 5** - Voltage rating (120 = 1200 V)
- 6** - P = Lead (Pb)-free

CIRCUIT CONFIGURATION



LINKS TO RELATED DOCUMENTS	
Dimensions	www.vishay.com/doc?95036
Packaging information	www.vishay.com/doc?95037



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